

Operational experience and performance of the Belle II Silicon Vertex Detector after the first SuperKEKB Long Shutdown

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Belle II Silicon Vertex Detector

- SuperKEKB [1] and Belle II [2]** [1] Y. Ohnishi et al., *PTEP* 2013, 03A011 (2013). [2] T. Abe et al., *arXiv:1011.0352*.
- SuperKEKB collides 7 GeV e^- with 4 GeV e^+ at $\sqrt{s} = 10.58$ GeV
 - Target instantaneous luminosity 6×10^{35} cm⁻²s⁻¹ to collect 50 ab⁻¹ data sample
 - Belle II records collision data for precision measurements and searches for beyond-the-standard-model physics
- Belle II Silicon Vertex Detector (SVD) [3]** [3] K. Adamczyk et al., *JINST* 17 P11042 (2022)
- The SVD consists of 4 layers of double-sided silicon-strip detectors (DSSDs), which are outside 2 layers of pixel detectors (PXD)
 - The DSSDs are 300~320 μ m thick and have readout strip pitch 50/75 μ m (P side), 160/240 μ m (N side)
 - Readout with APV25 ASIC that has a 50 ns shaping time
 - Provides precise hit information for tracking and vertexing, as well as dE/dx information for particle identification

Belle II Vertex Detector: VXD = SVD + PXD

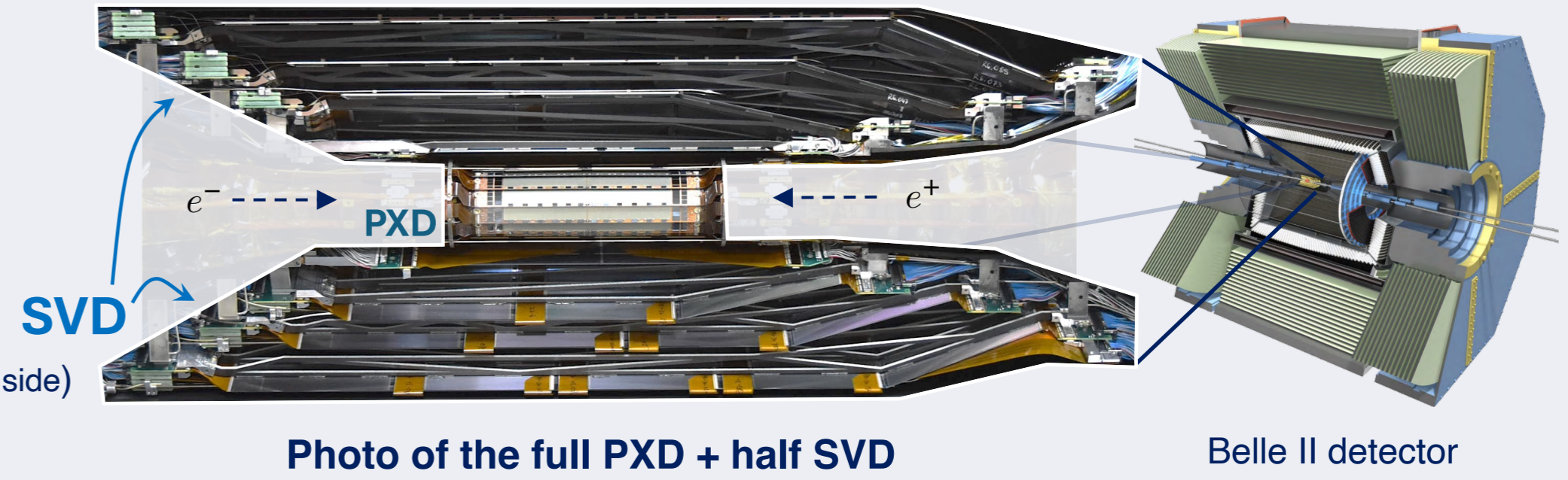


Photo of the full PXD + half SVD

Belle II detector

Timeline and operations

VXD reinstatement

SVD performance after LS1

Cluster Charge Collection

Radiation damage study

2022 June

2024 January

We are Here! Just beginning

Run 1

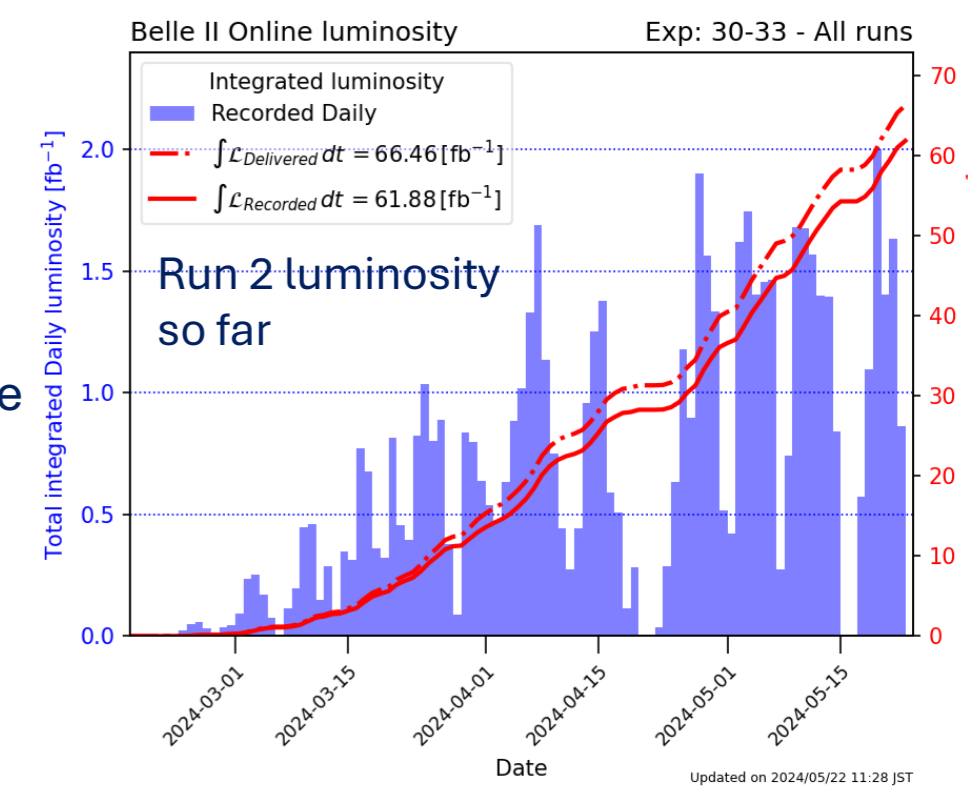
Long Shutdown 1

Run 2

- Recorded integrated luminosity $\mathcal{L} : 426$ fb⁻¹
- Achieved instantaneous luminosity $\mathcal{L} : 4.7 \times 10^{34}$ cm⁻²s⁻¹
- Smooth and stable operation without major issue
- Excellent SVD performance
 - ✓ Good SNR (13-30)
 - ✓ Large hit efficiency ($\geq 99\%$)
 - ✓ Masked strips < 1%

- VXD reinstatement with new PXD modules with the same SVD
- SVD was split into its two halves to allow the new PXD installation
- Several SVD tests were performed at each step of the VXD reinstatement to check its condition and spot problems
- Lowered cooling temperature to accommodate a higher PXD power consumption
- Checked the VXD alignment and performance using cosmic ray after reinstatement \rightarrow confirmed good performance

- Smooth and stable operation
- Physics performance is as good as Run 1
- SuperKEKB is trying to increase its beam current and optimize beam condition to achieve higher instantaneous luminosity
- Higher background dose is anticipated, we monitor the SVD status continuously
 - Checking noise, calibration constant, and leakage current
- \Rightarrow No severe damage observed so far

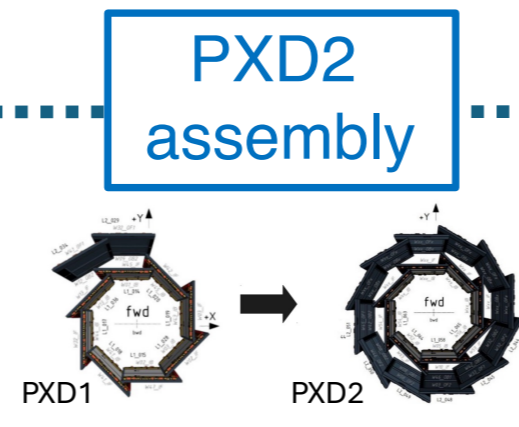
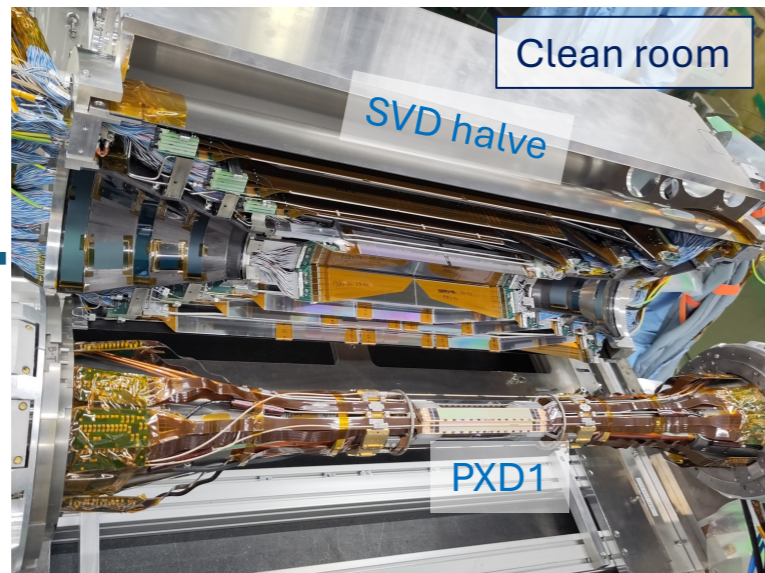
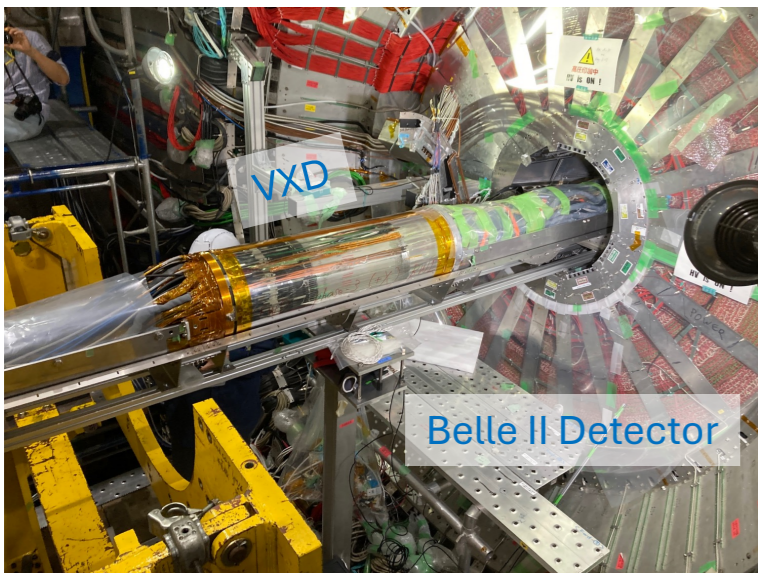


1 VXD extraction

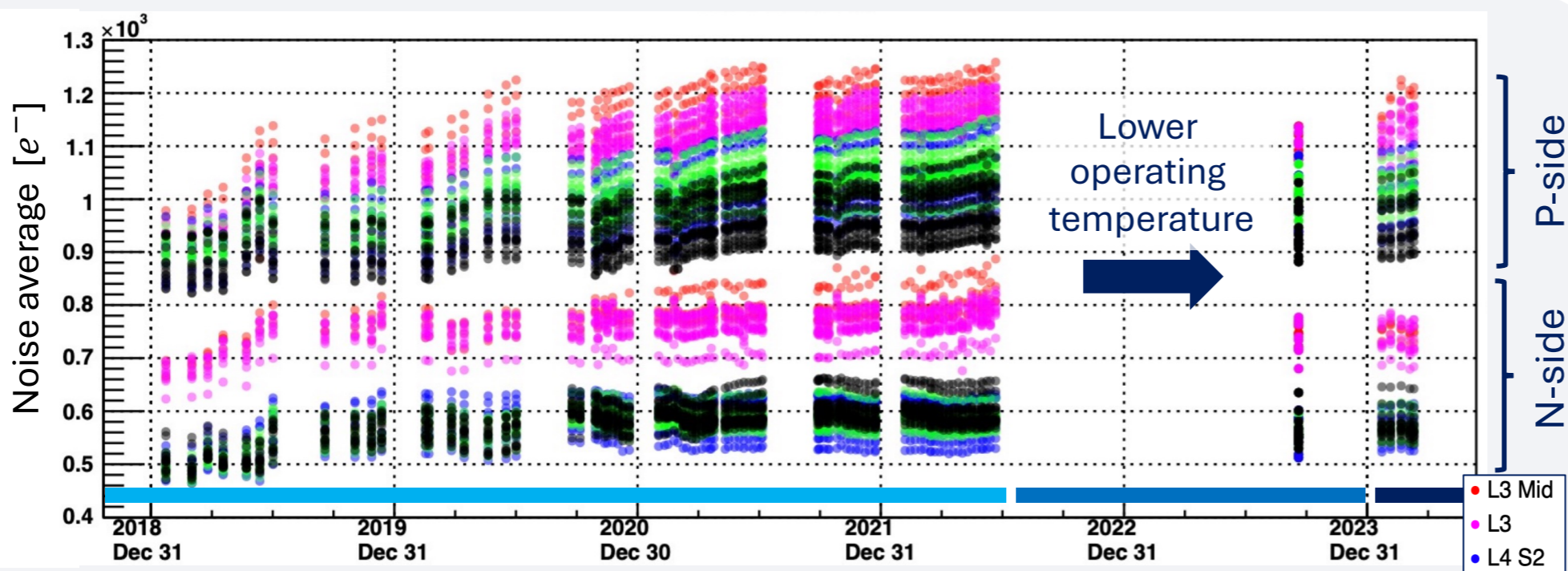
2 SVD detachment from PXD1

3 SVD attachment to PXD2

4 New VXD installation

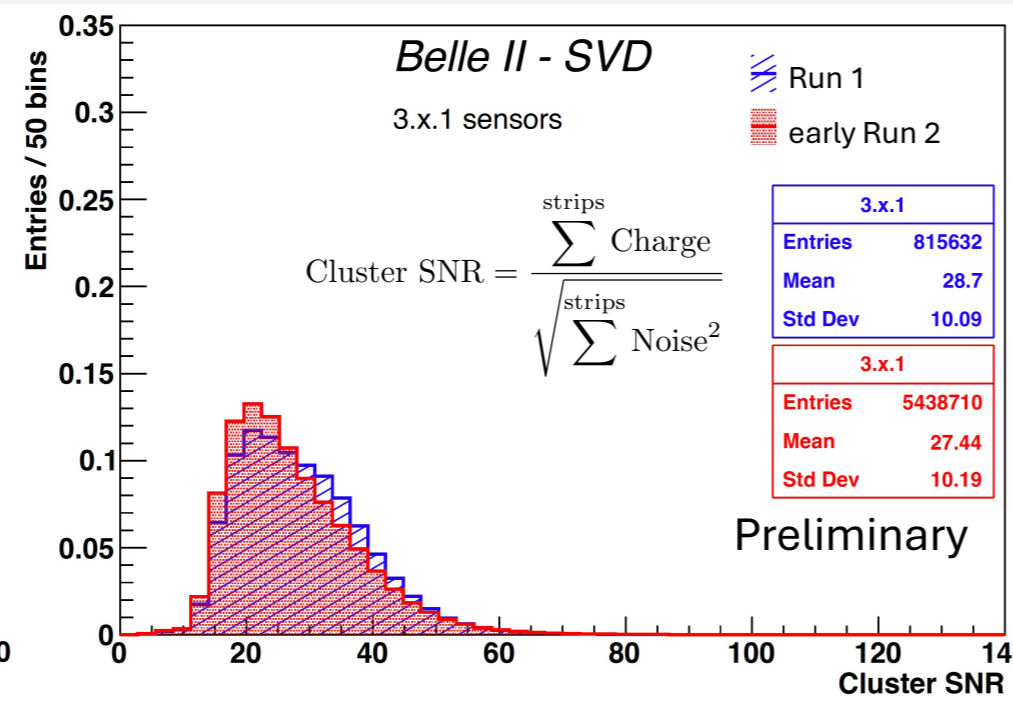
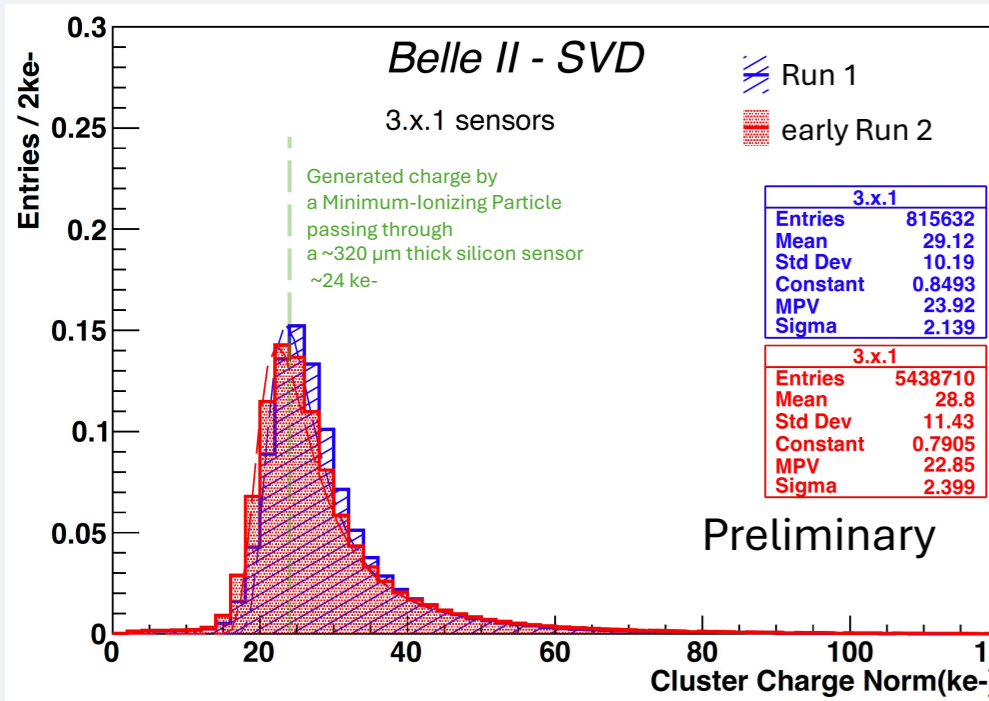


All successfully done



- Noise increased by 10 ~ 30% during Run 1 due to radiation damage on the sensors
 - Measured radiation dose in Layer 3 is < 70 krad during Run 1
- Reduction in noise by up to 10% during LS1 due to lower operating temperature and annealing effect on the sensor
- Physics performance with Run 2 noise level is as good as Run 1

Stable level, as expected



- No significant changes in the cluster charge and cluster SNR from Run1. Small variation due to temperature effects still not corrected.
- ✓ Hit efficiency also keeps high $\geq 99\%$
- ✓ Number of total masked strips $\sim 1\%$
- ✓ No evidence of the radiation damage having impacted the full depletion voltage

Physics performance in Run2 as good as in Run1

- A 90 MeV e^- beam irradiated SVD sensors up to 10 Mrad at ALPH, Tohoku Univ.
 - Estimated radiation dose is 0.35 Mrad/year on layer 3 with design luminosity
 - ✓ Type inversion occurs at 2 Mrad, equivalent neutron fluence 6×10^{12} n_{eq}/cm²
 - ✓ Linear correlation between dose and leakage current as NIEL hypothesis
 - ✓ The correlation is confirmed in the installed SVD sensors, and its slope is consistent with the irradiation study
 - ✓ **Type inverted irradiated sensor confirmed to collect charge well after 10 Mrad irradiated**

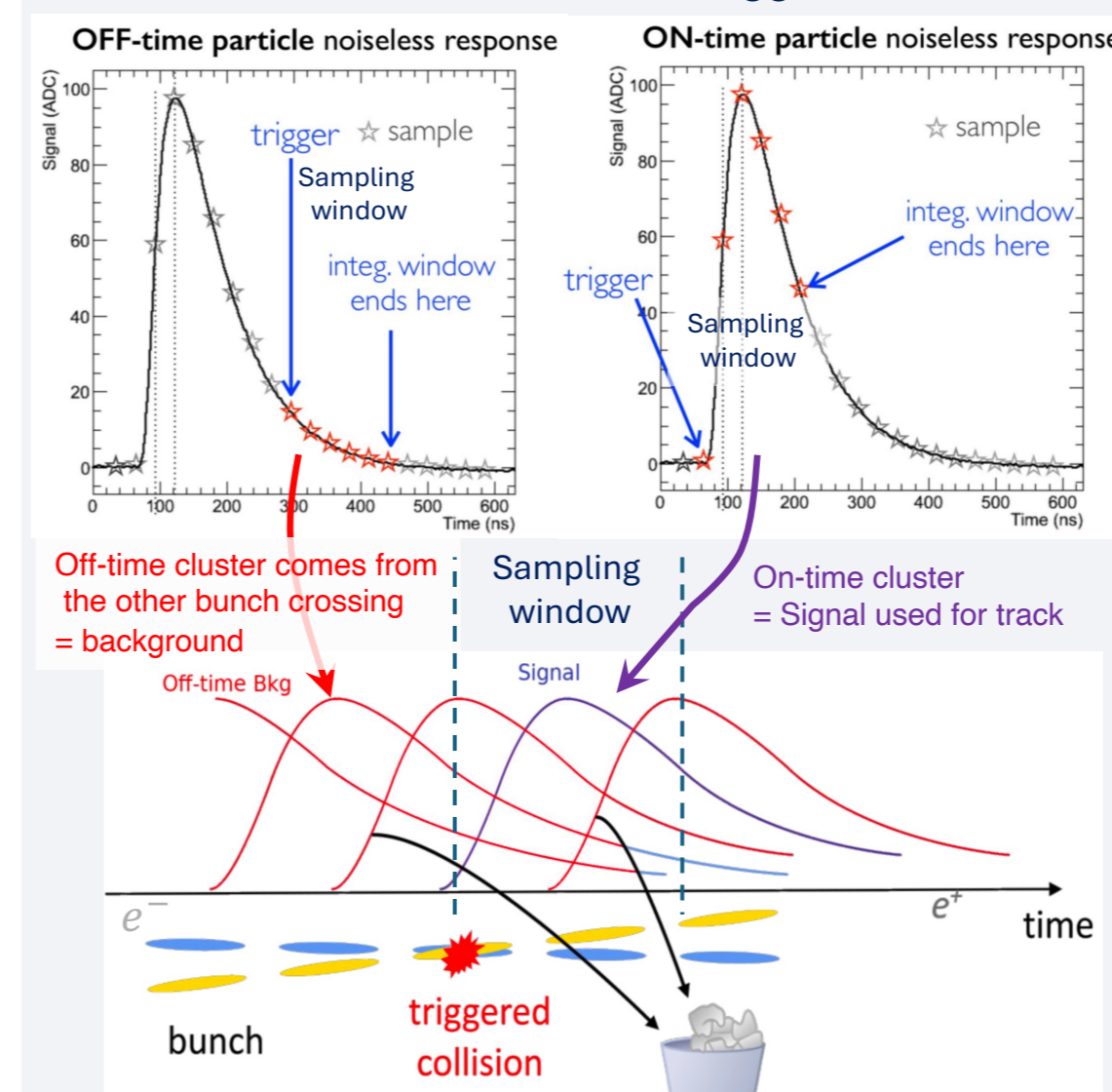
we have a good safety margin

Future background rejection

- Current hit occupancy is below 1%, but it is expected to rise as the background increases with higher beam luminosity in the future
- Higher occupancy degrades tracking performance by increasing the number of fake tracks
- We will implement hit-time selection and cluster-grouping methods, which are based on hit time to reject background and enhance occupancy acceptance,
 - With excellent hit-time resolution (< 3 ns) to remove off-time tracks
 - SVD has a feature that offers a 2000 times faster computing speed than a central drift chamber to provide collision time (T_0). It speeds up the High-Level Trigger reconstruction and helps it cope with HLT reconstruction in the high luminosity condition

Hit-time selection

- The hit time t is determined by the peak part of the signal sampling in the sampling window (6 samples).
- The peak position in the sampling window varies with the collision, enabling the identification of hits from triggered collisions

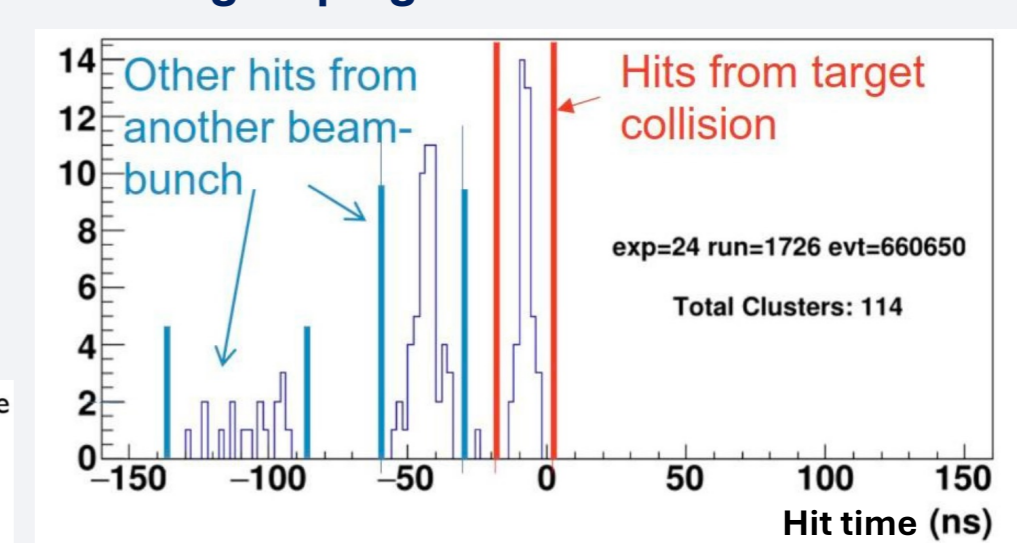


- Apply simple selection on hit time
 - $|t_u, v| < 50$ ns
 - $|t_u - t_v| < 20$ ns

\Rightarrow Removed 50% off-time track with keeping signal efficiency > 99%

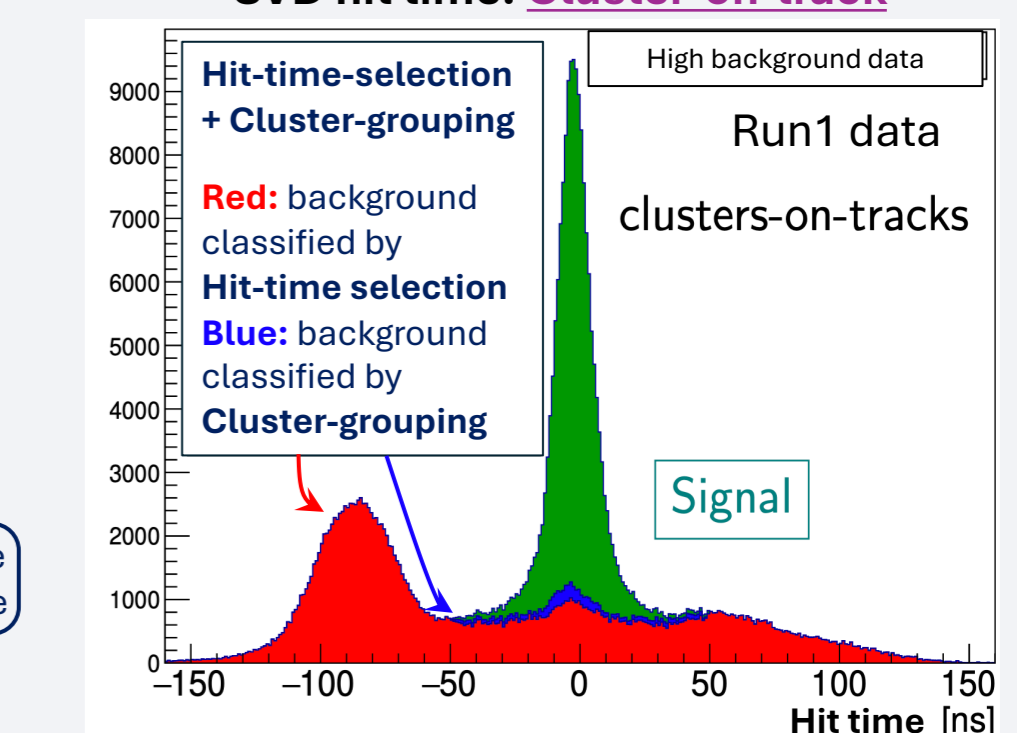
- ✓ Hit-time-selection can reject the red background area and the cluster-grouping can reject additional fake signals (blue area) coming from the off-time cluster contamination
- ✓ **These improvements lead to an increase in acceptable occupancy for track reconstruction to about 6% in layer 3**

Cluster-grouping



- Classified hit time with respect to trigger on an event-by-event basis.
- Select a group close to 0 and prominent as a signal group to form tracks

\Rightarrow Fake track rate can be reduced by 15%, outperforming the hit-time selection method



Applied both methods to classified

Ongoing study SNR at each sampling point of the APV25 differs between the background and the signal \rightarrow Useful for 3-sample sampling to reject bkg and to reduce the SVD DAQ dead time